

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10590632	JENSEN ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Young J Kim	1637

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Patent Databases (USPT, USPPG, EPO, JPO, DERWENT, IBM-TDB)	9/15/2008	/YJK/
see enclosed for text-search strategy	9/15/2008	/YJK/
updated - patent databases search - see enclosed for text-search strategy	5/13/2009	/YJK/
updated - patent databases search - see enclosed for text-search strategy	3/9/2010	/YJK/
updated	6/19/2010	/YJK/
updated	9/29/2010	/YJK/

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
	Interference search - see enclosed for search strategy	3/9/2010	/YJK/

	/Young J Kim/ Primary Examiner.Art Unit 1637
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